

Notice of References Cited	Application/Control No. 10/646,892	Applicant(s)/Patent Under Reexamination MAEDA, HITOSHI	
	Examiner David A. Rogers	Art Unit 2856	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,461,605	10-1995	Takimoto et al.	369/126
	C	US-6,461,907	10-2002	Imai, Kiyotaka	438/217
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	E	US-5,581,083	12-1996	Majumdar et al.	250/306
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Matey et al., "Scanning Capacitance Microscopy", 01 March 1995, Journal of Applied Physics, Vol. 5, No. 5, pages 1437-1444.
	V	Steeves et al., "Ultrafast Scanning Tunneling Microscopy", 2002, pages 1-51.
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.